

Application/Control No.	Applicant(s)/Patent under Reexamination	_
10/017,268	CROSS ET AL.	
Examiner	Art Unit	
Srilakshmi K. Kumar	2629	

SEARCHED				
Class	Subclass	Date	Examiner	
Update	Search	9/30/2006	SKK	
349	155	9/30/2006	SKK	
345	178	9/30/2006	SKK	
178	18	9/30/2006	SKK	
Update	Search	4/22/2007	SKK	
Update	Search	12/17/2007	SKK	
345	156-184	12/17/2007	SKK	
257	59	12/17/2007	SKK	
977	all	12/21/2007	SKK	
438	99,347	12/26/2007	SKK	
427	58-126.6	12/26/2007	SKK	
427	466-486	12/26/2007	SKK	

INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
	!				
See Interfer	ence Search	12/17/2007	SKK		

SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
Update Search, consulted Lun Yi Lao and Ke Xiao	9/30/2006	SKK
Update Search and consulted Kent CHang	4/24/2007	SKK
Update Search and consulted SPE, Amare Mengistu	12/17/2007	SKK
Consulted Nanotechnology Subject Matter Experts, Matthew Such AU 2891, and Shean Wu AU 1795	12/26/2007	SKK
STIC Nanotechnology Website, and nanotechnology database websites, IEEE, INSPEC, SID, The AMC Portal	12/21/2007	SKK